**EMC Component Testing Surrogate Data Submission**

**Section A – Supporting Documentation/Data provided**

JLR Test Plan / MOC Reference: ……………………………………............

Test report reference(s): ……………………………………………..

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| **Section B – Declarations****Authored by (Test Laboratory Representative)** |
|  |  |  |  |  |
| Name |  | Signature |  | Date |
|  |
| **Reviewed by (Supplier EMC expert)**  |
|  |  |  |  |  |
| Name |  | Signature |  | Date |
|  |
| **Reviewed by (JLR Component Engineer)**  |
|  |  |  |  |  |
| Name |  | Signature |  | Date |
|  |
| **Reviewed by (JLR EMC Engineer)**  |
|  |  |  |  |  |
| Name |  | Signature |  | Date |

**Section C – Test Summary**

|  |  |  |  |  |  |
| --- | --- | --- | --- | --- | --- |
| **JLR****Test ID** | **Test****Applies** | **Test already performed that****meets or exceeds JLR****Requirement?** | **Status****(see below)** | **Comments / Differences / Reasoning** | **Further****Test****Required?** |
| ***e.g. RI112*** |[x] [x]  *Not performed* | *Test level in surrogate data 96dbuA in range 15-30MHz. JLR requirement 106dBuA.*  |[x]
| **RI112** |[ ] [ ]  Not performed |  |[ ]
| **RI114** |[ ] [ ]  Not performed |  |[ ]
| **RI115** |[ ] [ ]  Not performed |  |[ ]
| **RI130** |[ ] [ ]  Not performed |  |[ ]
| **RI140** |[ ] [ ]  Not performed |  |[ ]
| **RI150** |[ ] [ ]  Not performed |  |[ ]
| **CI210** |[ ] [ ]  Not performed |  |[ ]
| **CI220** |[ ] [ ]  Not performed |  |[ ]
| **CI230** |[ ] [ ]  Not performed |  |[ ]
| **CI250** |[ ] [ ]  Not performed |  |[ ]
| **CI265** |[ ] [ ]  Not performed |  |[ ]
| **CI270** |[ ] [ ]  Not performed |  |[ ]
| **CI280** |[ ] [ ]  Not performed |  |[ ]
| **RE310** |[ ] [ ]  Not performed |  |[ ]
| **RE320** |[ ] [ ]  Not performed |  |[ ]
| **CE410** |[ ] [ ]  Not performed |  |[ ]
| **CE420** |[ ] [ ]  Not performed |  |[ ]

Guidance Notes:-

|  |  |
| --- | --- |
| **JLR Test ID** | The test ID as stated in the latest JLR EMC Component Specification |
| **Test Applies** | Select the checkbox if the test is applicable according to the JLR approved component test plan |
| **Test already performed that meets or exceeds JLR Requirement?** | Select the checkbox if surrogate data is being submitted, i.e. testing has already been performed to another OEM specification. The supplier EMC expert (or equivalent) is expected to perform an assessment comparing the test(s) performed with the requirements of the JLR EMC component specification and approved test plan. Items to consider include:● DUT Operating mode(s)?● Interface(s) tested?● Functional class required?● Functional class met?● Test level / port / pulse / waveform?● DUT Variant(s) / feature(s) / function(s)? |
| **Status** | **Non-compliant** | ● Test performed to JLR requirement or equivalent. ● Result non-compliant. ● Action plan for compliance required. ● Further testing likely to be required. |
| **Compliant** | ● Test performed to JLR requirement or equivalent. ● Result compliant. ● No further testing required. |
| **Not performed** | ● Test not performed to JLR requirement. ● Further testing required. |
| **Not required** | ● Test not applicable to this category of part according to JLR EMC spec. ● No Further testing required. |
| **Comments / Differences / Reasoning** | Further detail explaining differences between the tests performed and the requirements that are applicableComments and justification as to why no further testing is required (where applicable). |
| **Further Test Required?** | Select the checkbox if further testing is required (according to Status column above). This will be the list of tests which will be required in order to obtain compliance to the JLR EMC specification. |

**Surrogate data may only be used if its origin is from a lab meeting, as a minimum, the following criteria:**

1. **The Lab must have accreditation to ISO 17025**
2. **The Lab must gain accreditation by an ILAC MRA\*\* signatory body to perform testing to the following Intentional Standards:**
* **ISO 11452-4   Bulk Current Injection**
* **ISO 11452-2   Radiated Immunity (Anechoic Chamber)**
* **ISO 11452-9   Radiated Immunity from Portable Transmitters.**
* **ISO 7637-2   Transient Immunity**
* **ISO 7637-3   Transient Immunity**
* **IEC CISPR 25 Radiated Emissions**
* **ISO 10605   Electrostatic Discharge**